GUJARAT TECHNOLOGICAL UNIVERSITY

Master of Engineering
Subject Code: 3726103
Semester – II
Subject Name: Memory Technologies

Type of course: Elective

Prerequisite: NA

Rationale:

Teaching and Examination Scheme:

Teaching Scheme			Credits	Examination Marks				Total Marks
L	T	P	C	Theory Marks		Practical Marks		
				ESE(E)	PA (M)	PA (V)	PA (I)	
3	0	2	4	70	30	30	20	150

Content:

Sr. No.	Content	Total Hrs
1	Random Access Memory Technologies: Static Random Access Memories (SRAMs), SRAM Cell Structures, MOS SRAM Architecture, MOS SRAM Cell and Peripheral Circuit, Bipolar SRAM, Advanced SRAM Architectures, Application Specific SRAMs.	
2	DRAMs, MOS DRAM Cell, BiCMOS DRAM, Error Failures in DRAM, Advanced DRAM Design and Architecture, Application Specific DRAMs.SRAM and DRAM Memory controllers.	
3	Non-Volatile Memories: Masked ROMs, PROMs, Bipolar & CMOS PROM, EEPROMs, Floating Gate EPROM Cell, OTP EPROM, EEPROMs, Non-volatile SRAM, Flash Memories	
4	Semiconductor Memory Reliability and Radiation Effects: General Reliability Issues, RAM Failure Modes and Mechanism, Nonvolatile Memory, Radiation Effects, SEP, Radiation Hardening Techniques. Process and Design Issues, Radiation Hardened Memory Characteristics, Radiation Hardness Assurance and Testing.	
5	Advanced Memory Technologies and High-density Memory Packing Technologies: Ferroelectric Random Access Memories (FRAMs), Gallium Arsenide (GaAs) FRAMs, Analog Memories, Magneto Resistive Random Access Memories (MRAMs), Experimental Memory Devices.	
6	Memory Hybrids (2D & 3D), Memory Stacks, Memory Testing and Reliability Issues, Memory Cards, High Density Memory Packaging	

Reference Books:

1. Ashok K Sharma, "Advanced Semiconductor Memories: Architectures, Designs and Applications", Wiley Interscience
2. Kiyoo Itoh, "VLSI memory chip design", Springer International Edition
3. Ashok K Sharma," Semiconductor Memories: Technology, Testing and Reliability , PHI

GUJARAT TECHNOLOGICAL UNIVERSITY

Master of Engineering
Subject Code: 3726103

Course Outcome:

After learning the course the students should be able to:

Sr. No.	CO statement	Marks % weightage
CO-1	Select architecture and design semiconductor memory circuits and subsystems	
CO-2	Identify various fault models, modes and mechanisms in semiconductor memories and their testing procedures	
CO-3	Knowhow of the state-of-the-art memory chip design	